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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/837,877	04/19/2001	Shunpei Yamazaki	0756-2298	8131
22204	7590	09/14/2005		
NIXON PEABODY, LLP 401 9TH STREET, NW SUITE 900 WASHINGTON, DC 20004-2128			EXAMINER LEWIS, MONICA	
			ART UNIT	PAPER NUMBER
			2822	

DATE MAILED: 09/14/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

Office Action Summary	Application No.	Applicant(s)	
	09/837,877	YAMAZAKI ET AL.	
	Examiner	Art Unit	
	Monica Lewis	2822	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 29 June 2005.
- 2a) ☒ This action is **FINAL**. 2b) ☐ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1-20 and 22-24 is/are pending in the application.
- 4a) Of the above claim(s) 2,3,10-16,23 and 24 is/are withdrawn from consideration.
- 5) ☐ Claim(s) _____ is/are allowed.
- 6) ☒ Claim(s) 1,4-9,17-20 and 22 is/are rejected.
- 7) ☐ Claim(s) _____ is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☒ The drawing(s) filed on 02 December 2002 is/are: a) ☒ accepted or b) ☐ objected to by the Examiner.
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some * c) ☒ None of:
1. ☒ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. _____.
3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
- * See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- | | |
|--|---|
| 1) <input checked="" type="checkbox"/> Notice of References Cited (PTO-892) | 4) <input type="checkbox"/> Interview Summary (PTO-413)
Paper No(s)/Mail Date. _____ |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | 5) <input type="checkbox"/> Notice of Informal Patent Application (PTO-152) |
| 3) <input type="checkbox"/> Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)
Paper No(s)/Mail Date _____ | 6) <input type="checkbox"/> Other: _____ |

DETAILED ACTION

1. This action is in response to the amendment filed June 29, 2005.

Specification

2. The lengthy specification has not been checked to the extent necessary to determine the presence of all possible minor errors. Applicant's cooperation is requested in correcting any errors of which applicant may become aware in the specification.

Response to Arguments

3. Applicant's arguments with respect to claims 1, 4-9, 17-20 and 22 have been considered but are moot in view of the new ground(s) of rejection.

Claim Rejections - 35 USC § 103

4. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

5. Claims 1, 4-6, 9, 17-20 and 22 are rejected under 35 U.S.C. 103(a) as obvious over Kawasaki et al. (U.S. Patent No. 6,424,012) in view of Ogawa et al. (U.S. Patent No. 6,362,507).

In regards to claim 1, Kawasaki et al. ("Kawasaki") discloses the following:

a) the pixel TFF has a channel formation region (407) formed over a first wiring line (403) with a first insulating layer (402) interposed, and has a low concentration impurity region (406) that is in contact with the channel formation region and overlaps the first wiring line (For Example: See Figure 8b);

b) the storage capacitor is formed from a capacitor wiring line (415), a semiconductor region (414) that has the same composition as the channel formation region or the low concentration impurity region, a part of the insulating layer and wherein the first wiring line and the capacitor wiring line are formed on the same layer (For Example: See Figure 8b); and

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c) wherein a second wiring line (416) is formed over the channel formation region with a second insulating layer (419) interposed therebetween (For Example: See Figure 8b).

In regards to claim 1, Kawasaki fails to disclose the following:

a) a second wiring line does not overlap the low concentration impurity region.

However, Ogawa et al. ("Ogawa") discloses the use of a second wiring line (846) that does not overlap the low concentration impurity region (For Example: See Figure 19). It would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the semiconductor device of Kawasaki to include the use of a second wiring line that does not overlap the low concentration impurity region as disclosed in Ogawa because it aids in improving the reliability and the operation performance of the device (For Example: See Abstract).

Additionally, since Kawasaki and Ogawa are both from the same field of endeavor, the purpose disclosed by Ogawa would have been recognized in the pertinent art of Kawasaki.

In regards to claim 4, Kawasaki fails to disclose the following:

a) the first wiring line is appropriately a conductive film mainly containing an element selected from the group consisting of tantalum (Ta), chromium (Cr), titanium (Ti), tungsten (W), molybdenum (Mo), and silicon (Si), or an alloy film or silicide film containing the above elements in combination, or a laminate of the conductive films, the alloy films, or the silicide films.

However, Ogawa discloses the use of a first wiring line that contains titanium (For Example: See Column 9 Lines 25-30). It would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the semiconductor device of Kawasaki to include the use of titanium as disclosed in Ogawa because it aids in improving the reliability and the operation performance of the device (For Example: See Abstract).

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Additionally, since Kawasaki and Ogawa are both from the same field of endeavor, the purpose disclosed by Ogawa would have been recognized in the pertinent art of Kawasaki.

In regards to claim 5, Kawasaki discloses the following:

a) the channel formation region of the pixel TFT and the semiconductor region of the storage capacitor are formed of the same semiconductor layer (For Example: See Figure 8b).

In regards to claim 6, Kawasaki discloses the following:

a) the first insulating layer is appropriately an oxide or halogenated compound containing an element selected from the group consisting of tantalum (Ta), titanium (Ti), barium (Ba), hafnium (Hf), bismuth (Bi), tungsten (W), thorium (Th), and lead (Pb) (For Example: See Column 19 Lines 45-51).

In regards to claim 9, Kawasaki discloses the following:

a) the pixel TFT is connected to the source wiring line (416) and the gate wiring line, and the storage capacitor is formed under the source wiring line and/or the gate wiring line (For Example: See Figure 8b).

In regards to claim 17, Kawasaki discloses the following:

a) semiconductor device is an active matrix liquid crystal display or an active matrix EL display (For Example: See Column 1 Lines 5-22).

In regards to claim 18, Kawasaki discloses the following:

a) semiconductor device is a video camera, a digital camera, a projector, a projection TV, a goggle type display, an automobile navigation system, a personal computer, or a portable information terminal (For Example: See Column 1 Lines 5-22).

In regards to claim 19, Kawasaki discloses the following:

a) a cross section of the first wiring is taper shaped (For Example: See Figure 8b).

In regards to claim 20, Kawasaki discloses the following:

a) a cross section of the capacitor wiring line is taper shaped (For Example: See Figure 8b).

In regards to claim 22, Kawasaki discloses the following:

a) wherein the insulating layer comprises a first insulating layer and a second insulating layer (For Example: See Figure 8b and Column 19 Lines 45-51).

6. Claim 7 is rejected under 35 U.S.C. 103(a) as obvious over Kawasaki et al. (U.S. Patent No. 6,424,012) in view of Ogawa et al. (U.S. Patent No. 6,362,507) and Someya et al. (U.S. Publication No. 2002/0080295).

In regards to claim 7, Kawasaki discloses the following:

a) the first wiring line (For Example: See Figure 8b).

In regards to claim 7, Kawasaki fails to disclose the following:

a) floating state.

However, Someya et al. ("Someya") discloses the use of floating state (For Example: See Paragraph 148). It would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the semiconductor device of Kawasaki to include the use of floating state as disclosed in Someya because it aids in preventing deterioration (For Example: See Paragraph 148 and 149).

Additionally, since Kawasaki and Someya are both from the same field of endeavor, the purpose disclosed by Someya would have been recognized in the pertinent art of Kawasaki.

7. Claim 8 is rejected under 35 U.S.C. 103(a) as obvious over Kawasaki et al. (U.S. Patent No. 6,424,012) in view of Ogawa et al. (U.S. Patent No. 6,362,507) and Murade (U.S. Publication No. 2001/0030722).

In regards to claim 8, Kawasaki discloses the following:

a) the first wiring line (For Example: See Figure 8b).

In regards to claim 8, Kawasaki fails to disclose the following:

- a) the first wiring line is kept at the lowest power supply electric potential.

However, Murade discloses the use of the lowest potential (For Example: See Paragraph 15). It would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the semiconductor device of Kawasaki to include the use of the lowest potential as disclosed in Murade because it aids in preventing deterioration (For Example: See Paragraph 15).

Additionally, since Kawasaki and Murade are both from the same field of endeavor, the purpose disclosed by Murade would have been recognized in the pertinent art of Kawasaki.

Conclusion

8. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.


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9. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Monica Lewis whose telephone number is 571-272-1838.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Amir Zarabian can be reached on 571-272-1852. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300 for regular and after final communications. Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is 703-308-0956.

ML

September 9, 2005


AMIR ZARABIAN
EXAMINER
SEP 10 2005